EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3756711	substrate wafer semiconductor mask photomask (photo adj mask)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:39
L2	483118	1 same (inspect$ detect$ defect)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:44
L3	2086184	sensiti$7 major killer	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:45
L4	42760	2 same 3	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:42
L5	64599	1 near (inspect$ detect$ defect)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:44
L6	3912	5 same (sensiti$7 major killer)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:53
L7	181	"382"/$.ccls. and 6	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:53
L8	626	"356"/$.ccls. and 6	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:53

EAST Search History

L9	85	"348"/$.ccls. and 6	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:56
L10	855	gradation near difference	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:57
L11	4	6 and 10	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:57
L12	1	(sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 11:59
L13	421	(sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/08/01 12:00
L14	1	(sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:00
L15	16	"382"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect)	US-PGPUB	OR	ON	2007/08/01 12:01
L16	1	"382"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:01
L17	0	"348"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:01

L18	0	"356"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:01

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	1	(sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:00
L15	16	"382"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect)	US-PGPUB	OR	ON	2007/08/01 12:01
L16	1	"382"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:01
L17	0	"348"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:01
L18	0	"356"/$.ccls. and (sensiti$6 and semiconductor and surface and predetermin$4 and threshold and function and arithmetic and parameter and defect).clm.	US-PGPUB	OR	ON	2007/08/01 12:01

INTERFERENCE TEXT SEARCH